PTO/SB/08 A & B (modified)

Substitute for Form 1449 A & B/PTO				*Complete if Known*	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Application Number	Cont. of Serial No. 09/425,886
				Confirmation Number	Not Yet Assigned
				Filing Date	June 24, 2003
				First Named Inventor	Pranav ASHAR et al.
(use as many sheets as necessary)				Art Unit	~~Not Yet Assigned~~ 2133
				Examiner Name	~~Not Yet Assigned~~ ABRAHAM
Sheet	2	of	2	Attorney Docket Number	A8612

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Document Number: Number	Document Number: Kind Code[2] (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Foreign Patent Document: Country Code[3]	Foreign Patent Document: Number[4]	Foreign Patent Document: Kind Code[5] (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation[6]

OTHER ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation[6]
EA		SENTOVICH, E., et al. "Sequential Circuit Design Using Synthesis and Optimization", Proceedings of ICCD, 1992	
EA		GUPTA, A., ASHAR, P., "Integrating a Boolean Satisfiability and BDDS for Combinational Verification, Proceedings of VLSI Design 98, pp. 222-225, 1998	
EA		BURCH, J. and SINGHAI, V., "Tight Integration of Combinational Verification Methods", Proceedings of ICCAD, pp. 570-576, 1978	
EA		TOMITA, M., SUGANUMA, N., and HIRANO, K., "Pattern generation for locating logic design errors", IEICE Transactions Fundamentals, vol. E77-A, 1994	

Examiner Signature	Eyal Abraham	Date Considered	~~06~~ 06/24/04

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Sheet 1 of 2

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Examiner Initials*	Cite No.[1]	Document Number: Number	Document Number: Kind Code[2] (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
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Examiner Signature	Isaac Abraham	Date Considered	06/25/04

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